

N-channel TrenchMOS intermediate level FET Rev. 1 — 12 July 2011

Product data sheet

1. **Product profile**

1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Suitable for standard and logic level gate drive sources

1.3 Applications

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control

1.4 Quick reference data

Table 1 Quick reference data

- Suitable for thermally demanding environments due to 175 °C rating
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

| Table 1. | Quick reference data | | | | | | |
|-------------------|-------------------------------------|--|------------|-----|-----|-----|------|
| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
| V _{DS} | drain-source voltage | T _j ≥ 25 °C; T _j ≤ 175 °C | | - | - | 40 | V |
| I _D | drain current | V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> | <u>[1]</u> | - | - | 90 | A |
| P _{tot} | total power dissipation | T _{mb} = 25 °C; see <u>Figure 2</u> | | - | - | 128 | W |
| Static cha | racteristics | | | | | | |
| R _{DSon} | drain-source on-state resistance | $V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 11}{100000000000000000000000000000000$ | | - | 5.2 | 6.2 | mΩ |



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| Table 1. | Quick reference data | continued | | | | |
|----------------------|--|---|-----|-----|-----|------|
| Symbol | Parameter | Conditions | Min | Тур | Мах | Unit |
| Avalanch | e ruggedness | | | | | |
| E _{DS(AL)S} | non-repetitive drain-source avalanche energy | $ \begin{split} I_D &= 90 \text{ A}; V_{sup} \leq 40 \text{ V}; \\ R_{GS} &= 50 \Omega; V_{GS} = 10 \text{ V}; \\ T_{j(\text{init})} &= 25 ^\circ\text{C}; \text{ unclamped} \end{split} $ | - | - | 113 | mJ |
| Dynamic | characteristics | | | | | |
| Q _{GD} | gate-drain charge | $I_D = 25 \text{ A}; V_{DS} = 32 \text{ V};$ $V_{GS} = 10 \text{ V}; \text{ see } \underline{Figure 13};$ see $\underline{Figure 14}$ | - | 20 | - | nC |

[1] Continuous current is limited by package.

2. Pinning information

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| Table 2. | Pinning | information | | |
|----------|---------|-----------------------------------|--------------------|----------------|
| Pin | Symbol | Description | Simplified outline | Graphic symbol |
| 1 | G | gate | | _ |
| 2 | D | drain | mb | |
| 3 | S | source | | |
| mb | D | mounting base; connected to drain | | mbb076 S |

SOT428 (DPAK)

3. Ordering information

| Table 3. Ordering | information | | |
|-------------------|-------------|---|---------|
| Type number | Package | | |
| | Name | Description | Version |
| BUK626R2-40C | DPAK | plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped) | SOT428 |

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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | | Min | Max | Unit |
|----------------------|---|--|------------------|-----|-----|------|
| V _{DS} | drain-source voltage | T _j ≥ 25 °C; T _j ≤ 175 °C | | - | 40 | V |
| V _{GS} | gate-source voltage | DC | <u>[1]</u> | -16 | 16 | V |
| | | Pulsed | [2] | -20 | 20 | V |
| I _D | drain current | T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> | [3] | - | 90 | А |
| | | T_{mb} = 100 °C; V_{GS} = 10 V; see <u>Figure 1</u> | | - | 70 | А |
| I _{DM} | peak drain current | T _{mb} = 25 °C; pulsed; t _p ≤ 10 μs; see <u>Figure 3</u> | | - | 397 | А |
| P _{tot} | total power dissipation | T _{mb} = 25 °C; see <u>Figure 2</u> | | - | 128 | W |
| T _{stg} | storage temperature | | | -55 | 175 | °C |
| Tj | junction temperature | | | -55 | 175 | °C |
| Source-drain | diode | | | | | |
| I _S | source current | T _{mb} = 25 °C | [3] | - | 90 | А |
| I _{SM} | peak source current | pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$ | | - | 397 | А |
| Avalanche rug | ggedness | | | | | |
| E _{DS(AL)S} | non-repetitive drain-source avalanche energy | $ I_D = 90 \text{ A}; \text{V}_{\text{sup}} \leq 40 \text{ V}; \text{R}_{\text{GS}} = 50 \Omega; \\ \text{V}_{\text{GS}} = 10 \text{ V}; \text{T}_{\text{j(init)}} = 25 ^{\circ}\text{C}; \text{ unclamped} $ | | - | 113 | mJ |
| E _{DS(AL)R} | repetitive drain-source avalanche energy | | <u>[4][5][6]</u> | - | - | J |

[1] -16V accumulated duration not to exceed 168 hrs.

[2] Accumulated pulse duration not to exceed 5mins.

[3] Continuous current is limited by package.

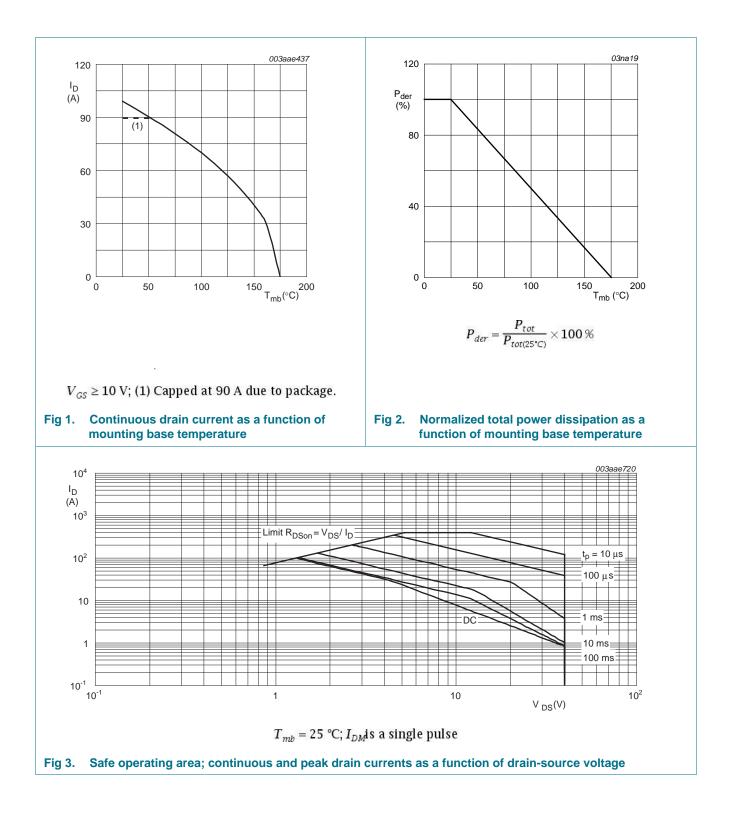
[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[6] Refer to application note AN10273 for further information.

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5. Thermal characteristics

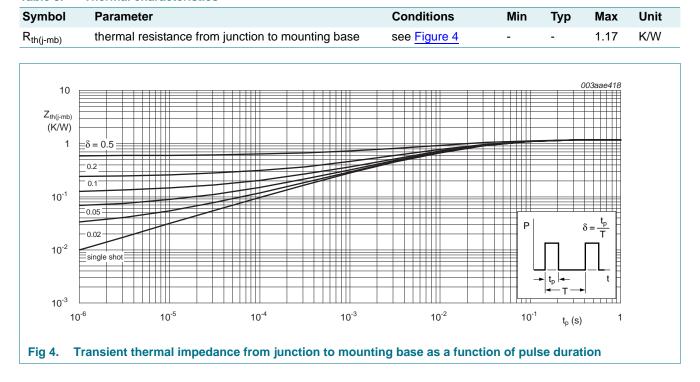


Table 5. Thermal characteristics

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6. Characteristics

| Table 6. | Characteristics | | | | | |
|----------------------|--------------------------------|---|-----|------|------|------|
| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
| Static cha | racteristics | | | | | |
| V _{(BR)DSS} | drain-source breakdown voltage | $I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ\text{C}$ | 40 | - | - | V |
| | | $I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$ | 36 | - | - | V |
| V _{GS(th)} | gate-source threshold voltage | $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u> | 1.8 | 2.3 | 2.8 | V |
| | | $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see Figure 9 | - | - | 3.3 | V |
| | | $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see <u>Figure 9</u> | 0.8 | - | - | V |
| I _{DSS} | drain leakage current | V_{DS} = 40 V; V_{GS} = 0 V; T_j = 175 °C | - | - | 500 | μA |
| | | V_{DS} = 40 V; V_{GS} = 0 V; T_j = 25 °C | - | 0.02 | 1 | μA |
| I _{GSS} | gate leakage current | $V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$ | - | 2 | 100 | nA |
| | | $V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$ | - | 2 | 100 | nA |
| R _{DSon} | | V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 11</u> | - | 5.2 | 6.2 | mΩ |
| | | V_{GS} = 5 V; I_D = 15 A; T_j = 25 °C; see <u>Figure 11</u> | - | 7 | 8.8 | mΩ |
| | | V_{GS} = 4.5 V; I_D = 15 A; T_j = 25 °C; see <u>Figure 11</u> | - | 8 | 10.7 | mΩ |
| | | V_{GS} = 10 V; I_D = 15 A; T_j = 175 °C; see <u>Figure 12</u> ; see <u>Figure 11</u> | - | - | 13 | mΩ |
| Dynamic | characteristics | | | | | |
| Q _{G(tot)} | total gate charge | $I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 13; see Figure 14 | - | 67 | - | nC |
| | | $I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 5 \text{ V};$ see Figure 13; see Figure 14 | - | 39 | - | nC |
| Q _{GS} | gate-source charge | $I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$ | - | 11 | - | nC |
| Q _{GD} | gate-drain charge | see Figure 13; see Figure 14 | - | 20 | - | nC |
| C _{iss} | input capacitance | $V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$ | - | 2790 | 3720 | pF |
| C _{oss} | output capacitance | $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 15}{1000}$ | - | 380 | 456 | pF |
| C _{rss} | reverse transfer capacitance | | - | 275 | 377 | pF |
| t _{d(on)} | turn-on delay time | $V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; V_{GS} = 10 \text{ V};$ | - | 16.7 | - | ns |
| t _r | rise time | $R_{G(ext)} = 10 \ \Omega$ | - | 48.6 | - | ns |
| t _{d(off)} | turn-off delay time | | - | 124 | - | ns |
| t _f | fall time | | - | 17 | - | ns |
| L _D | internal drain inductance | from upper edge of drain mounting base to centre of die ; $T_j = 25 \text{ °C}$ | - | 3.5 | - | nH |
| L _S | internal source inductance | from source lead to source bond pad ; $T_j = 25 \ ^{\circ}C$ | - | 7.5 | - | nH |

Symbol

Source-drain diode

BUK626R2-40C

Unit

Max

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Тур

Min

| 0 | source-drain voltage | $I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}$ see <u>Figure 16</u> | , · j, | | | 1.2 | |
|---|--|--|---|---|---|--|----|
| | reverse recovery time | I _S = 20 A; dI _S /dt = - | | - | 43 | - | ns |
| | recovered charge | $V_{\rm GS} = 0 \text{ V}; V_{\rm DS} = 28$ | 5 V | - | 56 | - | nC |
| | 00 |)3aae721 | | | | 003aae723 | |
| 100 I _D | $V_{GS}(V) = 10/6.0/5.0$ | 10 | | | | | |
| (A) | | (S) | | | | | |
| 80 - | | 3 | 0 | | | + | |
| | | | | | | | |
| 60 - | | 4.0 | 60 | | | | |
| 40 | | | | | | | |
| 40 | | 3.8 | 0 | | | | |
| 20 - | | 3.6 | 20 | | | | |
| 20 | | 3.4 | | | | | |
| 0 | | 3.2 | 0 | | | | |
| | | | | 40 | 60 | 80 10 | 0 |
| 0 | 0.25 0.5 0.75 _V | / _{DS} (V) ¹ | 0 20 | 40 | 00 | ⁸⁰ I _D (A) ¹⁰ | - |
| 0 | | ν _{DS} (V) ¹ | | | | | - |
| 0 | 0.25 0.5 0.75 $_{\rm V}$ $T_j = 25$ °C; $t_p = 300 \mu { m s}$ | / _{DS} (V) ¹ | | $= 25 ^{\circ}\text{C}; V_{L}$ | | | - |
| g 5. Oı | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur | rent as a Fig 6. | T _j Forward tra | = 25 °C; V_L | $\sigma_S = 15$ N | / | |
| g 5. Oı | $T_j = 25 \text{ °C}; t_p = 300 \ \mu \text{s}$ | rent as a Fig 6. | T_{j} | = 25 °C; V_L | $\sigma_S = 15$ N | / | |
| g 5. Oı | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | rrent as a Fig 6. | T _j Forward tra | = 25 °C; V_L | $\sigma_S = 15$ N | / | |
| g 5. Or ful ²⁵ R _{DSon} | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. Stypical values | T _j Forward tra drain currer | = 25 °C; V_L | $\sigma_S = 15$ N | / s a functio | |
| g 5. O t ful ²⁵ | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. Stypical values 132aae727 Image: Constraint of the second seco | T _j Forward tra drain currer | = 25 °C; V_L | $\sigma_S = 15$ N | / s a functio | |
| g 5. Ot ful ²⁵ R _{DSon} (mΩ) | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. Stypical values 132aae727 Image: Constraint of the second seco | T _j Forward tra drain currer | = 25 °C; V_L | $\sigma_S = 15$ N | / s a functio | |
| g 5. Ot ful ²⁵ R _{DSon} (mΩ) | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. Stypical values 132aae727 Image: Constraint of the second seco | T _j Forward tra drain currer | = 25 °C; V _L ansconduct nt; typical v | _S = 15 V ance as alues | | |
| g 5. Ot fu ²⁵ R _{DSon} (mΩ) 20 | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. Stypical values 132aae727 Image: Constraint of the second seco | T _j Forward tra drain currer | = 25 °C; V_L | _S = 15 V ance as alues | / s a functio | |
| g 5. Ot fu ²⁵ R _{DSon} (mΩ) 20 | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. Stypical values 132aae727 Image: Constraint of the second seco | T _j Forward tra drain currer | = 25 °C; V _L ansconduct nt; typical v | _S = 15 V ance as alues | | |
| g 5. Ot ful 25 R _{DSon} (mΩ) 20 15 | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. Stypical values 132aae727 Image: Constraint of the second seco | Tj Forward tradrain currer 60 45 30 | = 25 °C; V _L ansconduct nt; typical v | _S = 15 V ance as alues | | |
| g 5. Ot ful 25 R _{DSon} (mΩ) 20 15 | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. Stypical values 132aae727 Image: Constraint of the second seco | T _j Forward tra drain currer | = 25 °C; V _L ansconduct nt; typical v | _S = 15 V ance as alues | | |
| g 5. Or fun 25 R _{DSon} (mΩ) 20 15 | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. Stypical values 132aae727 Image: Constraint of the second seco | Tj Forward tradrain currer 60 45 30 | = 25 °C; V _L ansconduct nt; typical v | _S = 15 V ance as alues | | |
| g 5. Or fu 25 R _{DSon} (mΩ) 20 15 10 5 0 | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. 33aae727 Image: style | <i>T</i> _j Forward tra drain curren | = 25 °C; V_L insconduct nt; typical v $T_j = 17$ | os = 15 V ance as values | 003aae722 | |
| g 5. Or fun ²⁵ ^R _{DSon} (mΩ) 20 15 10 5 | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. Stypical values 132aae727 Image: Constraint of the second seco | T _j Forward traddrain curren 60 | = 25 °C; V _L ansconduct nt; typical v | os = 15 V ance as values | | |
| g 5. Or fu 25 R _{DSon} (mΩ) 20 15 10 5 0 | $T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage; | Fig 6. 33aae727 Image: style | <i>T</i> _j Forward trad drain curren | = 25 °C; V_L insconduct nt; typical v $T_j = 17$ | $p_S = 15$ M ance as values | 003aae722 | |

Conditions

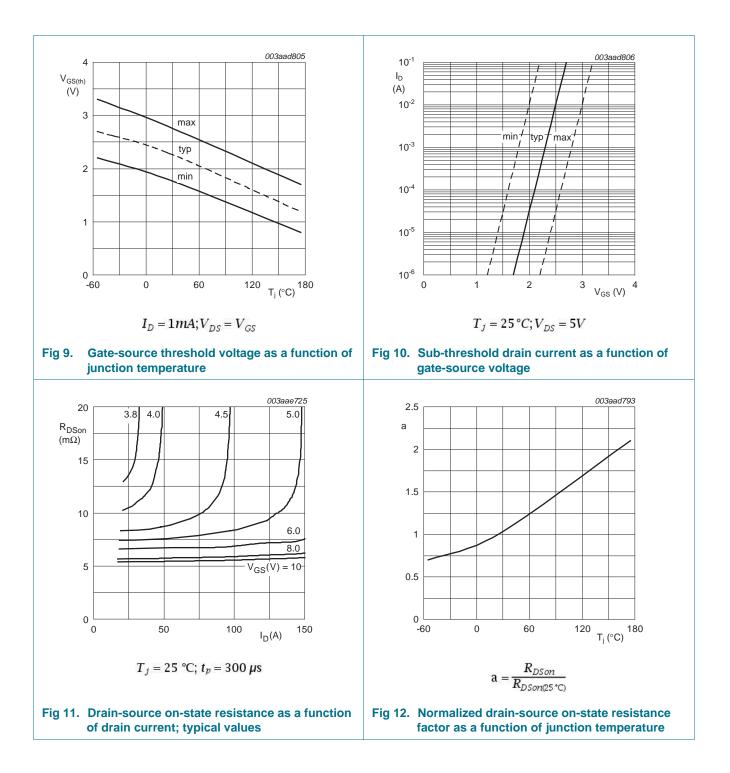
| Table 6. Characteristics con | ntinued |
|------------------------------|---------|
|------------------------------|---------|

Parameter

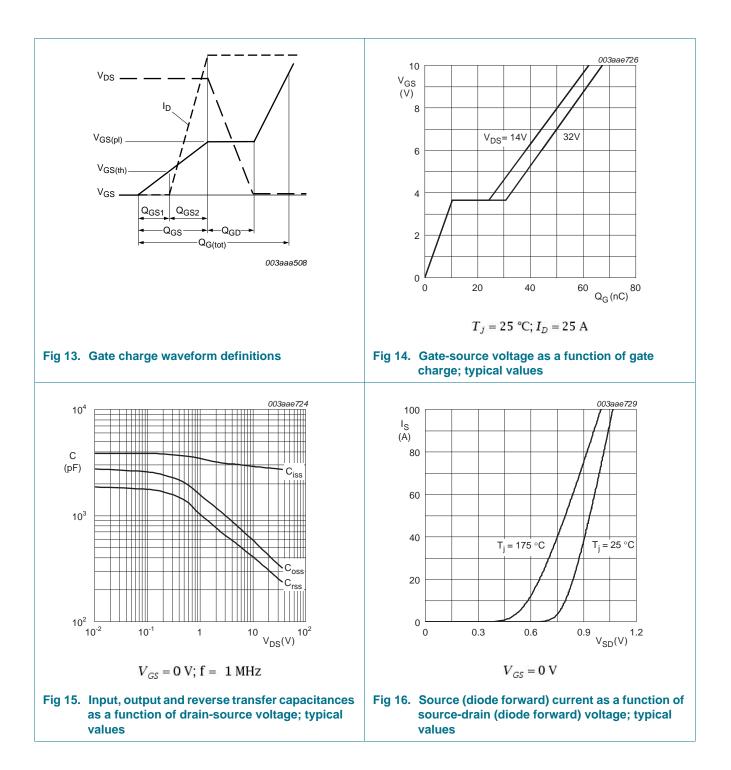
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7. Package outline

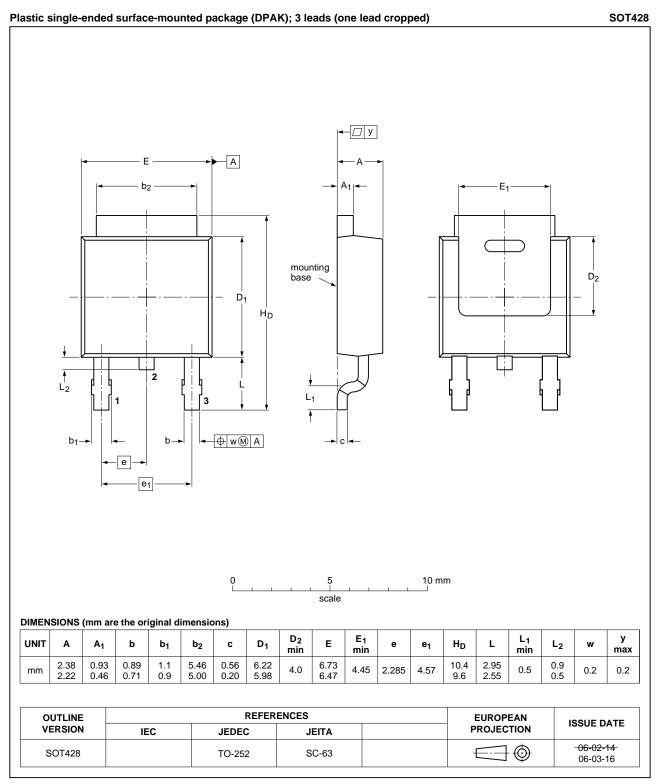


Fig 17. Package outline SOT428 (DPAK)

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8. Revision history

| Table 7. Revision h | Revision history | | | | | |
|---------------------|------------------|--------------------|---------------|------------|--|--|
| Document ID | Release date | Data sheet status | Change notice | Supersedes | | |
| BUK626R2-40C v.1 | 20110712 | Product data sheet | - | - | | |

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9. Legal information

9.1 Data sheet status

| Document status [1] [2] | Product status [3] | Definition |
|--------------------------------|--------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
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